

21. (New) A method of forming a thin film comprising the step of: forming an AgPdTi alloy thin film using a sputtering target material, the AgPdTi alloy comprising Pd in an amount ranging from 0.1 to 1.5 atomic %, Ti in an amount ranging from 0.1 to 2.9 atomic %, and Cu in an amount ranging from 0.1 to 3.5 atomic %.

*C 1*  
*Cont'd*

22. (New) The method of claim 21, wherein the thin film has a thickness from approximately 500 Angstroms to approximately 1500 Angstroms.

23. (New) The method of claim 21, wherein the wavelength is less than or equal to 650 nm.

24. (New) The method of claim 21, wherein the thin film has a thickness from approximately 500 Angstroms to approximately 1500 Angstroms; and wherein the wavelength is less than or equal to 650 nm.

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B. Rule 131 Affidavit - Correction

The applicants note that the Examiner was missing Exhibits A and B from the prior submitted Rule 131 affidavit. The entire affidavit plus the missing Exhibits are being re-filed. The contents of the affidavit having been established, Nee is no longer an available reference. Accordingly, Nee no longer anticipates the claims and the single reference obviousness rejection in view of Nee no longer applies.